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**PRODUCT BULLETIN**  
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**ISSUE DATE:** 23-Aug-2013  
**NOTIFICATION:** 15833  
**TITLE:** I.MX25 SECOND SITE FINAL TEST (SCS)  
**EFFECTIVE DATE:** 24-Aug-2013

**DEVICE(S)**

MPN
MCIMX250CJM4A
MCIMX250DJM4A
MCIMX253CJM4A
MCIMX253DJM4A
MCIMX257CJM4A
MCIMX257CJM4AR2
MCIMX257DJM4A
MCIMX257DJM4AR2
MCIMX258CJM4A

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**AFFECTED CHANGE CATEGORIES**

- SUBCONTRACTOR TEST SITE

**DESCRIPTION OF CHANGE**

Freescal Semiconductor is adding a second source external final test site, "SCS" (STATS-Singapore), for the i.MX25 17x17MAPBGA devices to assure flexible manufacturing capacity and continuity of supply. The current Freescal final test site is "TJN" (Tianjin, China).

See attached qualification results.

**REASON FOR CHANGE**

Adding a second final test site to maintain supply capacity and continuity.

**ANTICIPATED IMPACT OF PRODUCT CHANGE(FORM, FIT, FUNCTION, OR RELIABILITY)**

No impact to form, fit, function, or reliability.

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**NOTE:**

THE CHANGE(S) SPECIFIED IN THIS NOTIFICATION WILL BE IMPLEMENTED ON THE EFFECTIVE DATE LISTED ABOVE. To request further data or inquire about the notification, please enter a [Service Request](#)

For sample inquiries - please go to [www.freescale.com](http://www.freescale.com)

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**QUAL DATA AVAILABILITY DATE:** 15-Aug-2013

**QUALIFICATION STATUS:** COMPLETED

**QUALIFICATION PLAN:**

N/A

**RELIABILITY DATA SUMMARY:**

N/A

**ELECTRICAL CHARACTERISTIC SUMMARY:**

N/A

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**CHANGED PART IDENTIFICATION:**

N/A

**SAMPLE AVAILABILITY DATE:** 15-Aug-2013

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**ATTACHMENT(S):**

External attachment(s) FOR this notification can be viewed AT:  
[15833 i.MX25 Test Site Expansion Qualification 20130816.pdf](#)

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